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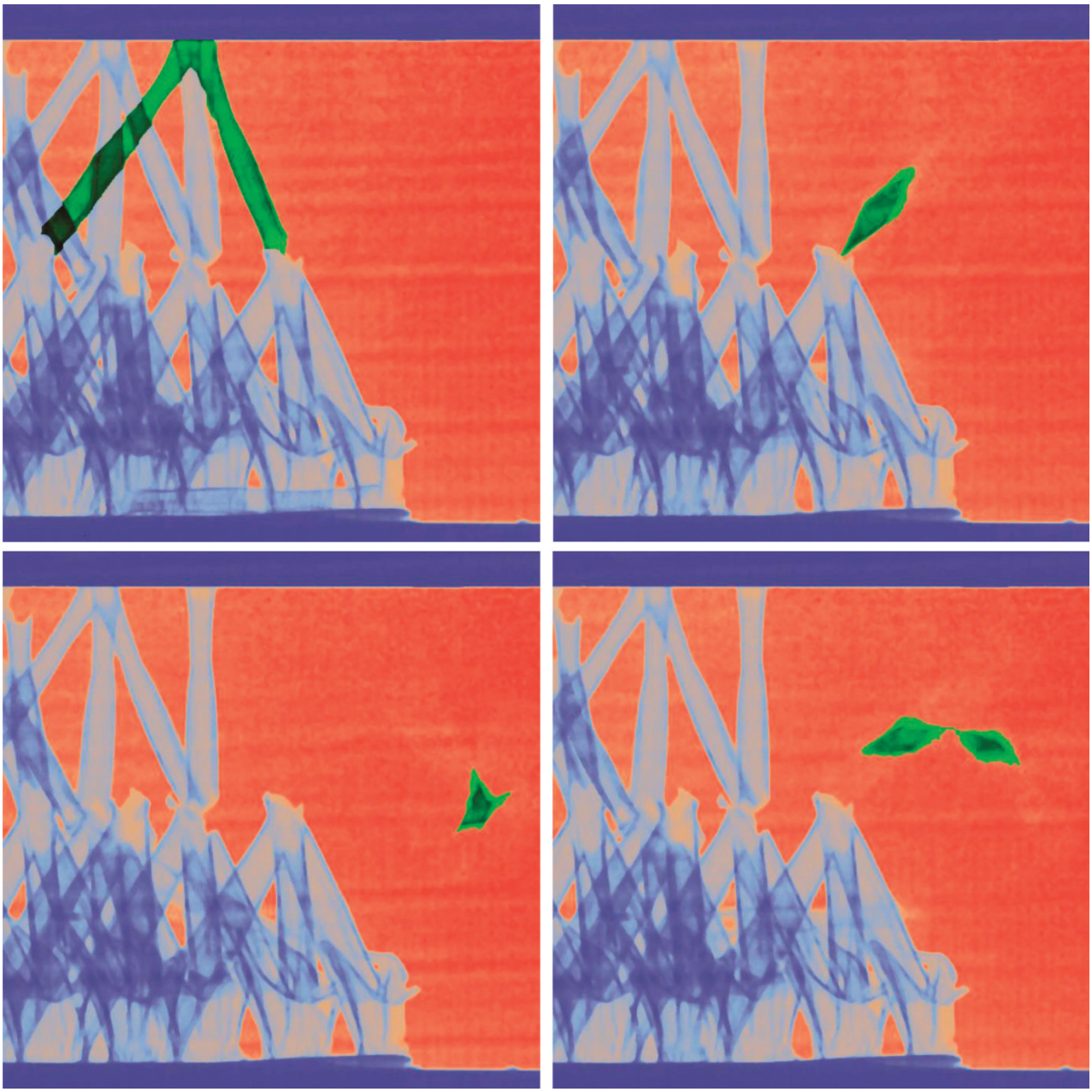

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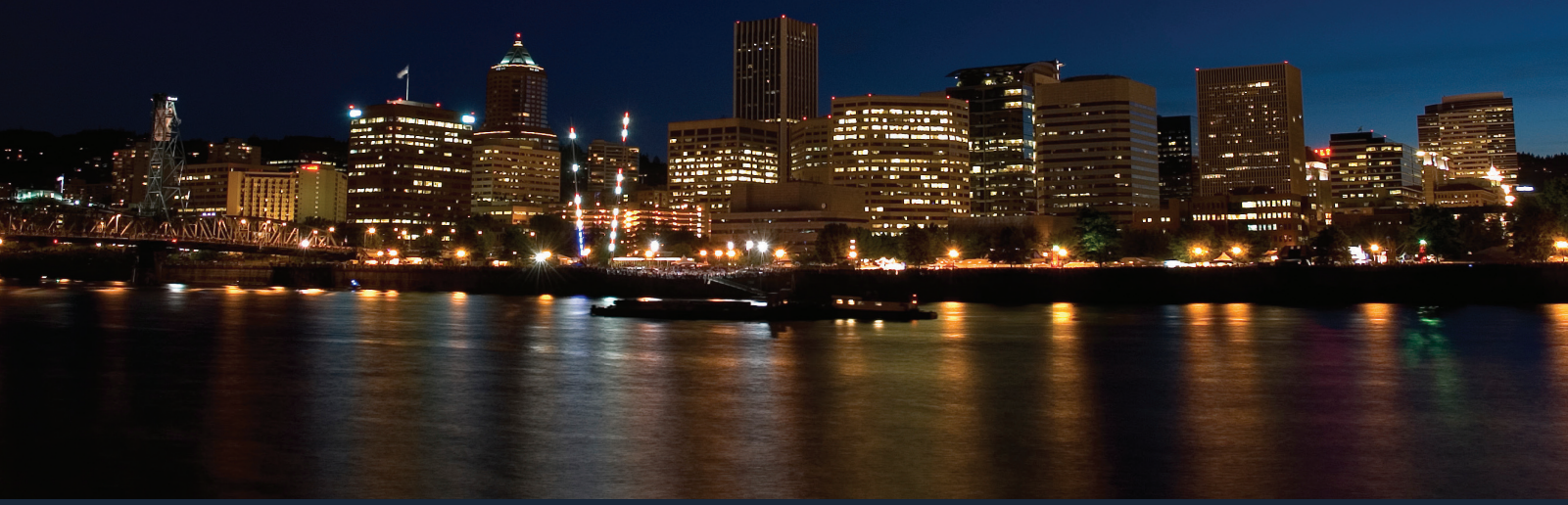

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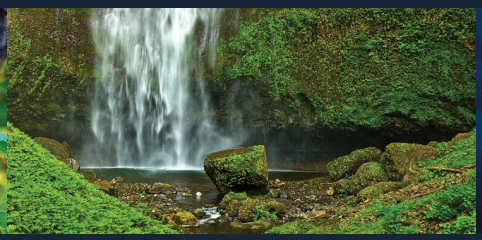

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Online Registration *(opens February 2015)* | **Portland Hotel Information** *(reservations available February 2015)*

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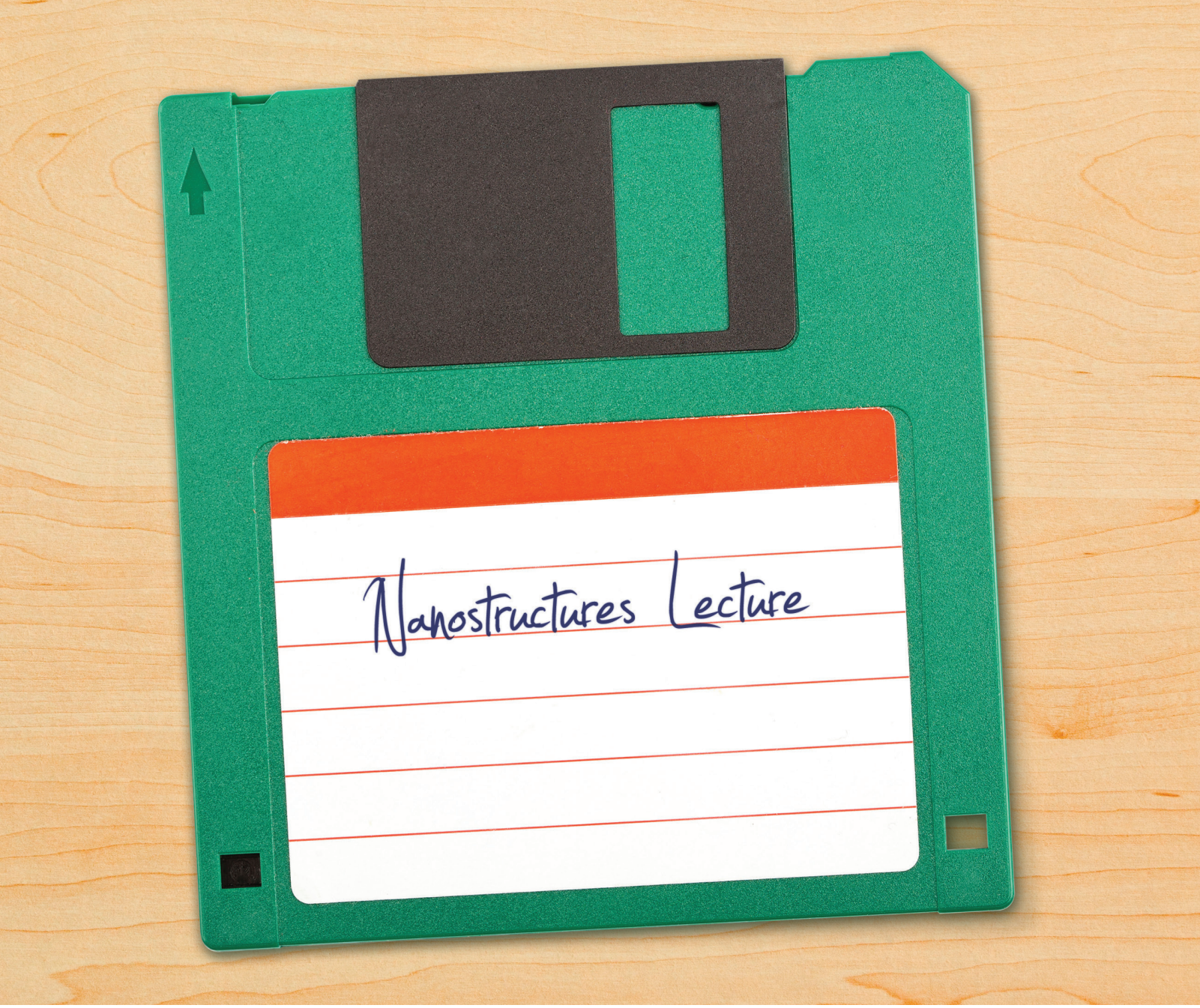
MAS Microanalysis Society

IMS International Metallographic Society ASM INTERNATIONAL



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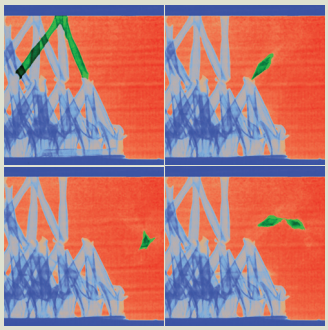

Clockwise from upper left: successive radiographs, 2 milliseconds apart, of an NiP microlattice during dynamic compression. Fragment in green broke from the sample. Full width = 3.4 mm.

See article by Cordes et al.

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